

Please replace the final paragraph of page 16 of the original application (lines 20-22) in its entirety with the following:

*B2*

In FIGURE 6, we depict the measurement of the thin imaged layer of photoresist taken by a spectrometer before and after the transfer. The presence of interference fringes indicates the presence of a thin film. The original spectrum in FIGURE 6(a) indicates a film is present on the original quartz carrier, while FIGURE 6(b) indicates no film is found on the silicon substrate. After transfer, the spectrum in FIGURE 6(c) indicates there is no film left on the quartz carrier, while the spectrum in FIGURE 6(d) indicates the presence of the film on the silicon substrate.

In the Drawings:

Please replace the original page 8 of the Drawings, containing Figure 6, with the enclosed substitute sheet.

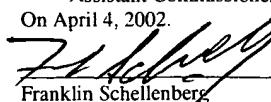
Respectfully submitted,

  
Franklin Schellenberg  
Registration No. 47,315

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as Express Mail in an envelope addressed to:

Assistant Commissioner for Patents, United States Patent and Trademark Office, Washington, DC 20231  
On April 4, 2002.

 4/4/2002  
Franklin Schellenberg Date